

Search Notes

Application/Control No.

10/813,015

Examiner

Brian S. Kwon

Applicant(s)/Patent under
Reexamination

FAHEY, JED W.

Art Unit

1614

SEARCHED

Class	Subclass	Date	Examiner
	see search notes	10/14/2007	BK
514	514		
	515		
	24		

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
Reference:	10/14/2007	BK
updated (STN, EAST, NPL)		
Updated (Continuity Data, Inventor Name)		